Applicant(s)/Patent Under Application/Control No. Reexamination 10/044,565 KUKREJA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Greg Bengzon 2144 **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 707/1 US-2003/0163438 A1 08-2003 Barnett et al. Α 09-2002 709/204 US-2002/0138572 A1 Delany et al. В US-2002/0128995 A1 09-2002 Muntz et al. 707/1 С US-2002/0133579 A1 09-2002 Bernhardt et al. 709/223 D 709/225 US-2002/0165960 A1 11-2002 Chan, Christine Wai Han Ε 06-2005 719/328 US-6,904,600 B1 James et al. F 05-2004 713/156 Carter et al. US-6,742,114 B1 G US-2003/0131020 A1 07-2003 Karamanolis et al. 707/200 н USı US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Name Classification Country MM-YYYY Country Code-Number-Kind Code Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Х